# **MOSFET** – Power, Single N-Channel

60 V, 6.8 mΩ, 71 A

# NVTYS006N06CL

#### Features

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low RDS(on) to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	60	V
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain	Steady State	$T_C = 25^{\circ}C$	۱ <sub>D</sub>	71	А
Current R <sub>θJC</sub> (Notes 1, 2, 3, 4)		T <sub>C</sub> = 100°C		50	
Power Dissipation		$T_{C} = 25^{\circ}C$	PD	61	W
$R_{\theta JC}$ (Notes 1, 2, 3)		T <sub>C</sub> = 100°C		31	
Continuous Drain	Steady	$T_A = 25^{\circ}C$	۱ <sub>D</sub>	16	А
Current R <sub>θJA</sub> (Notes 1, 3, 4)		T <sub>A</sub> = 100°C		11	
Power Dissipation	State	$T_A = 25^{\circ}C$	PD	3.2	W
$R_{\theta JA}$ (Notes 1, 3)		T <sub>A</sub> = 100°C		1.6	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \ \mu s$		I <sub>DM</sub>	322	А
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	–55 to +175	°C
Source Current (Body Diode)			۱ <sub>S</sub>	51	А
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 3.6 A)			E <sub>AS</sub>	115	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		ΤL	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 3)	$R_{\theta JC}$	2.4	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	47	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

2. Psi  $(\Psi)$  is used as required per JESD51–12 for packages in which substantially less than 100% of the heat flows to single case surface.

3. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.

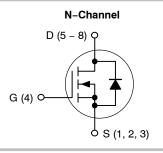
4. Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



# **ON Semiconductor®**

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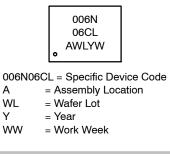
V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX	
60 V	6.8 mΩ @ 10 V	71 A	
00 V	10 mΩ @ 4.5 V		





LFPAK8 3.3x3.3 CASE 760AD

#### MARKING DIAGRAM



# **ORDERING INFORMATION**

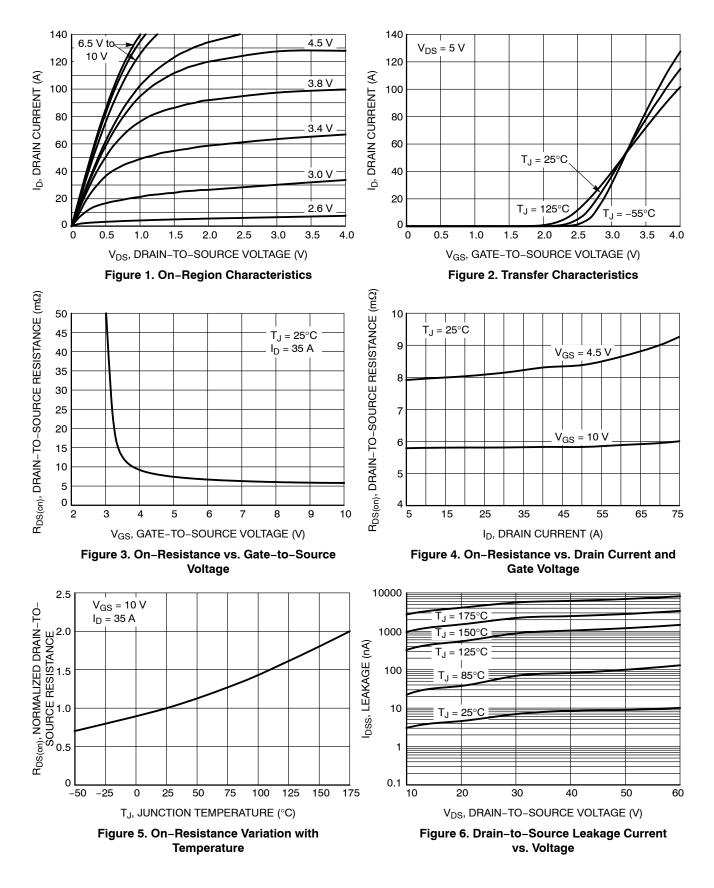
See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise specified)

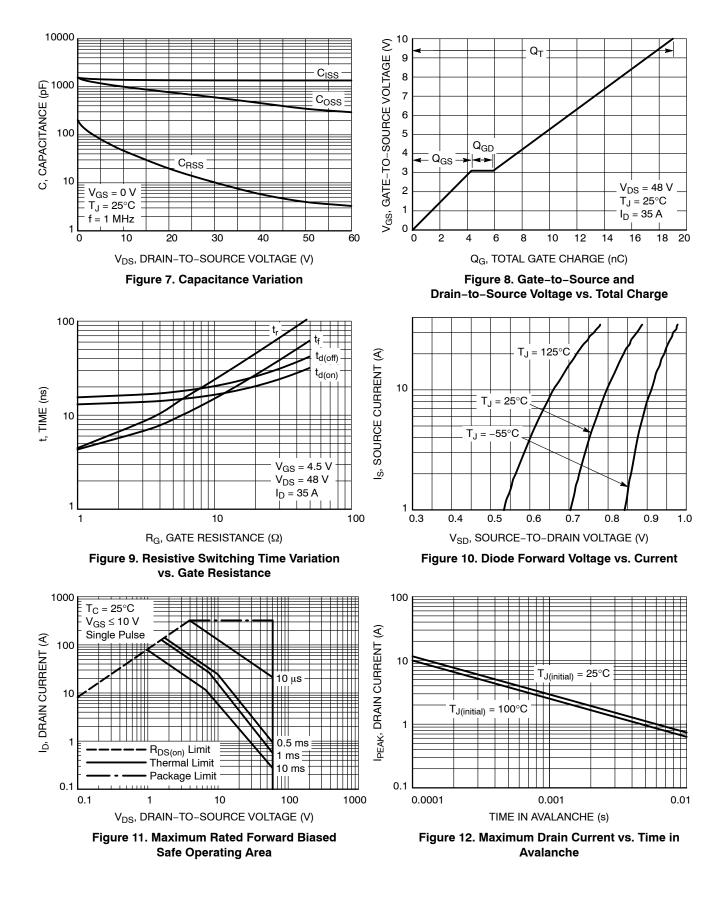
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					•		
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, I <sub>D</sub> = 250 µA		60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				28		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V_{.}$	$T_J = 25^{\circ}C$			10	μA
		V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 60 V	T <sub>J</sub> = 125°C			250	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 53 \ \mu A$		1.2		2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-4.8		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 35 A		5.8	6.8	mΩ
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 35 A		8.1	10	
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 5 V, I <sub>E</sub>	<sub>0</sub> = 35 A		67		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>				1330		pF
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MH	łz, V <sub>DS</sub> = 25 V		740		
Reverse Transfer Capacitance	C <sub>RSS</sub>				11		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 35 A			8		nC
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 48 V; $I_{D}$ = 35 A			19		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 35 A			2		nC
Gate-to-Source Charge	Q <sub>GS</sub>				4.3		1
Gate-to-Drain Charge	Q <sub>GD</sub>				1.6		1
Plateau Voltage	V <sub>GP</sub>				3.1		V
SWITCHING CHARACTERISTICS (Note 6	δ)						
Turn-On Delay Time	t <sub>d(ON)</sub>				13.6		ns
Rise Time	tr	V <sub>GS</sub> = 4.5 V. V			7.7		1
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 48 V, I <sub>D</sub> = 35 A, R <sub>G</sub> = 2.5 Ω			16.3		1
Fall Time	t <sub>f</sub>				6.1		
DRAIN-SOURCE DIODE CHARACTERIS	TICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$		0.9	1.2	V
		$I_{\rm S} = 35 \rm{A}$ $T_{\rm J} = 125^{\circ}\rm{C}$		0.8		1	
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dI <sub>S</sub> /d <sub>t</sub> = 100 A/µs, I <sub>S</sub> = 35 A			37		ns
Charge Time	t <sub>a</sub>				18		1
Discharge Time	t <sub>b</sub>				19		1
Reverse Recovery Charge	Q <sub>RR</sub>				22		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 6. Switching characteristics are independent of operating junction temperatures.

# **TYPICAL CHARACTERISTICS**



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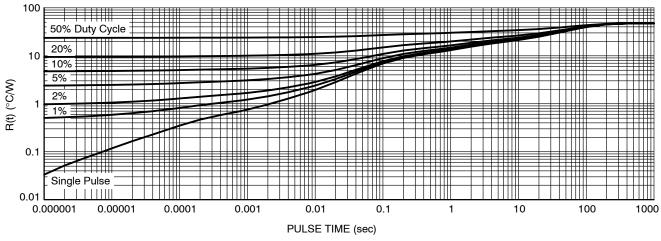


Figure 13. Thermal Characteristics

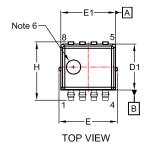
### **DEVICE ORDERING INFORMATION**

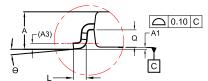
Device	Marking	Package	Shipping <sup>†</sup>
NVTYS006N06CLTWG	006N 06CL	LFPAK33	3000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

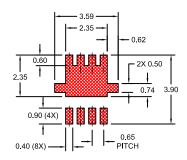
#### PACKAGE DIMENSIONS

LFPAK8 3.3x3.3, 0.65P CASE 760AD ISSUE E



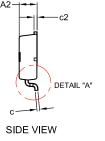


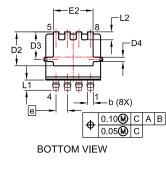
DETAIL 'A' SCALE: 2:1



LAND PATTERN RECOMMENDATION

\*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.





NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS OR BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.
- 6. OPTIONAL MOLD FEATURE.

DIM	MILLIMETERS				
Biw	MIN.	NOM.	MAX.		
А	0.95	1.05	1.15		
A1	0.00	0.05	0.10		
A2	0.95	1.00	1.05		
A3		0.15 RE	н		
b	0.27	0.32	0.37		
С	0.12	0.17	0.22		
c2	0.12	0.17	0.22		
D1	2.50	2.60	2.70		
D2	1.82	1.92	2.02		
D3	1.46	1.56	1.66		
D4	0.20	0.25	0.30		
E	3.20	3.30	3.40		
E1	3.00	3.10	3.20		
E2	2.15	2.25	2.35		
е	0.65 BSC				
Н	3.20	3.30	3.40		
L	0.25	0.37	0.50		
L1	0.48	0.58	0.68		
L2	0.35	0.45	0.55		
Q	0.45	0.50	0.55		
Φ	0°	4°	8°		

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